

**Notice of References Cited**

Application/Control No.

09/487,729

Applicant(s)/Patent Under  
Reexamination  
HAN, BAIK-HEE

Examiner

Paulos M. Natnael

Art Unit

2614

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6344882	02-2002	Shim et al.	348/731
	B	US-6400422	06-2002	Nakamura	348/732
	C	US-6400421	06-2002	Sakakibara	348/732
	D	US-5963269	10-1999	Beery	348/570
	E	US-6215531	04-2001	Beery	348/734
	F	US-6204888	03-2001	Kim	348/570
	G	US-6317168	11-2001	Seo	348/725
	H	US-4897727	01-1990	Richards	348/734
	I	US-5428405	06-1995	Lee	348/731
	J	US-5438377	08-1995	Chang	348/731
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.